



YOUSHANG SEMICONDUCTOR

**设计研发新型功率器件**

**各类小信号开关**

**中低压及高压大电流等场效应管**

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## Product Summary

BV <sub>DSS</sub>	R <sub>DS(ON)</sub>	I <sub>D</sub> T <sub>A</sub> = +25°C
-20V	710mΩ @ V <sub>GS</sub> = -4.5V	-0.63A
	930mΩ @ V <sub>GS</sub> = -2.5V	-0.55A
	1250mΩ @ V <sub>GS</sub> = -1.8V	-0.48A

## Features and Benefits

- Low On-Resistance
- Low Gate Threshold Voltage
- Low Input Capacitance
- Fast Switching Speed
- Low Input/Output Leakage

## Description and Applications

This new generation MOSFET is designed to minimize the on-state resistance (R<sub>DS(ON)</sub>) yet maintain superior switching performance, making it ideal for high-efficiency power-management applications.

- DC-DC converters
- Load switches
- Power-management functions

## Mechanical Data

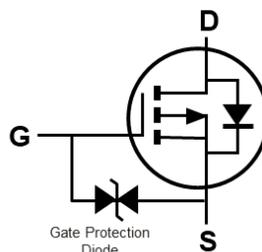
- Package: SOT523
- Package Material: Molded Plastic, "Green" Molding Compound. UL Flammability Classification Rating 94V-0
- Moisture Sensitivity: Level 1 per J-STD-020
- Terminals: Finish — Matte Tin Annealed over Alloy 42 Leadframe. Solderable per MIL-STD-202, Method 208 (e3)
- Terminal Connections: See Diagram
- Weight: 0.002 grams (Approximate)



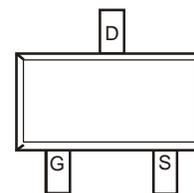
SOT523



Top View



Equivalent Circuit



Top View

**Maximum Ratings** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic	Symbol	Value	Unit	
Drain-Source Voltage	$V_{DSS}$	-20	V	
Gate-Source Voltage	$V_{GSS}$	$\pm 8$	V	
Continuous Drain Current (Note 6) $V_{GS} = -4.5\text{V}$	$I_D$	$T_A = +25^\circ\text{C}$ $T_A = +75^\circ\text{C}$	-0.63 -0.51	A
Maximum Continuous Body Diode Forward Current (Note 6)		$I_S$	-0.4	A
Pulsed Drain Current (10 $\mu\text{s}$ Pulse, Duty Cycle = 1%)	$I_{DM}$	-2.5	A	

**Thermal Characteristics** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic	Symbol	Value	Unit
Total Power Dissipation (Note 5)	$P_D$	0.26	W
Thermal Resistance, Junction to Ambient (Note 5)	$R_{\theta JA}$	480	$^\circ\text{C/W}$
Total Power Dissipation (Note 6)	$P_D$	0.44	W
Thermal Resistance, Junction to Ambient (Note 6)	$R_{\theta JA}$	287	$^\circ\text{C/W}$
Operating and Storage Temperature Range	$T_J, T_{STG}$	-55 to +150	$^\circ\text{C}$

**Electrical Characteristics** (@ $T_A = +25^\circ\text{C}$ , unless otherwise specified.)

Characteristic	Symbol	Min	Typ	Max	Unit	Test Condition
<b>OFF CHARACTERISTICS (Note 7)</b>						
Drain-Source Breakdown Voltage	$BV_{DSS}$	-20	—	—	V	$V_{GS} = 0\text{V}, I_D = -250\mu\text{A}$
Zero Gate Voltage Drain Current $T_J = +25^\circ\text{C}$	$I_{DSS}$	—	—	-1	$\mu\text{A}$	$V_{DS} = -20\text{V}, V_{GS} = 0\text{V}$
Gate-Source Leakage	$I_{GSS}$	—	—	$\pm 10$	$\mu\text{A}$	$V_{GS} = \pm 8\text{V}, V_{DS} = 0\text{V}$
<b>ON CHARACTERISTICS (Note 7)</b>						
Gate Threshold Voltage	$V_{GS(TH)}$	-0.5	—	-1.0	V	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$
Static Drain-Source On-Resistance	$R_{DS(ON)}$	—	390	710	m $\Omega$	$V_{GS} = -4.5\text{V}, I_D = -400\text{mA}$
		—	590	930		$V_{GS} = -2.5\text{V}, I_D = -300\text{mA}$
		—	770	1250		$V_{GS} = -1.8\text{V}, I_D = -100\text{mA}$
Diode Forward Voltage (Note 7)	$V_{SD}$	—	-0.8	-1.2	V	$V_{GS} = 0\text{V}, I_S = -300\text{mA}$
<b>DYNAMIC CHARACTERISTICS (Note 8)</b>						
Input Capacitance	$C_{iss}$	—	33	—	pF	$V_{DS} = -10\text{V}, V_{GS} = 0\text{V},$ $f = 1.0\text{MHz}$
Output Capacitance	$C_{oss}$	—	10	—	pF	
Reverse Transfer Capacitance	$C_{rss}$	—	3	—	pF	
Total Gate Charge	$Q_g$	—	1.4	—	nC	$V_{GS} = -4.5\text{V}, V_{DS} = -15\text{V},$ $I_D = -1\text{A}$
Gate-Source Charge	$Q_{gs}$	—	0.5	—	nC	
Gate-Drain Charge	$Q_{gd}$	—	0.1	—	nC	
Turn-On Delay Time	$t_{D(ON)}$	—	4.6	—	ns	$V_{DS} = -10\text{V}, I_D = -1\text{A}$ $V_{GS} = -4.5\text{V}, R_G = 6\Omega$
Turn-On Rise Time	$t_R$	—	2.2	—	ns	
Turn-Off Delay Time	$t_{D(OFF)}$	—	14.4	—	ns	
Turn-Off Fall Time	$t_F$	—	7.9	—	ns	

- Notes:
- Device mounted on FR-4 substrate PC board, 2oz copper, with minimum recommended pad layout.
  - Device mounted on FR-4 substrate PC board, 2oz copper, with 1inch square copper plate.
  - Short duration pulse test used to minimize self-heating effect.
  - Guaranteed by design. Not subject to production testing.

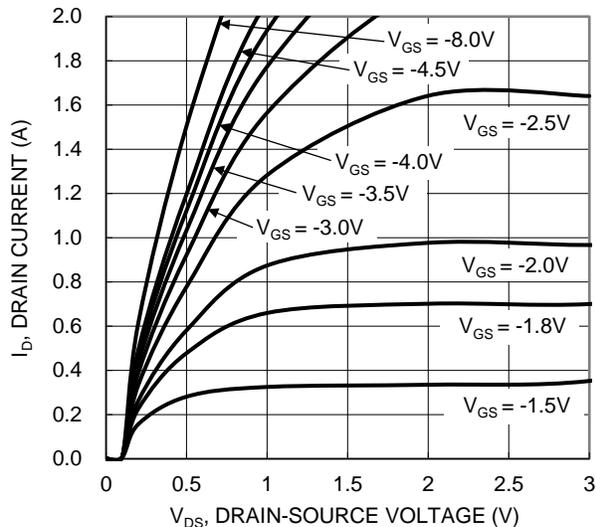


Figure 1. Typical Output Characteristic

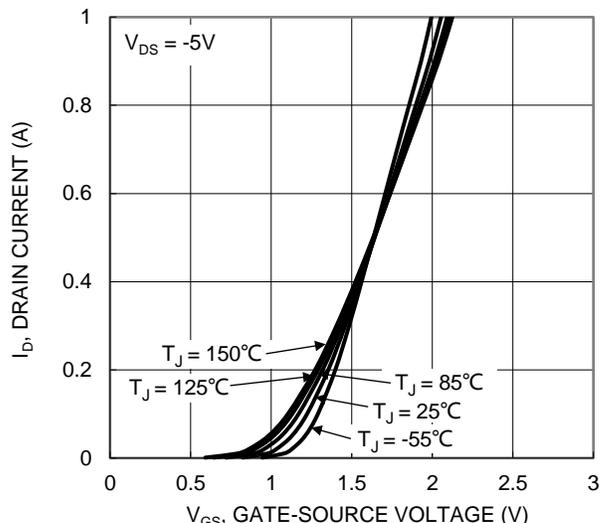


Figure 2. Typical Transfer Characteristic

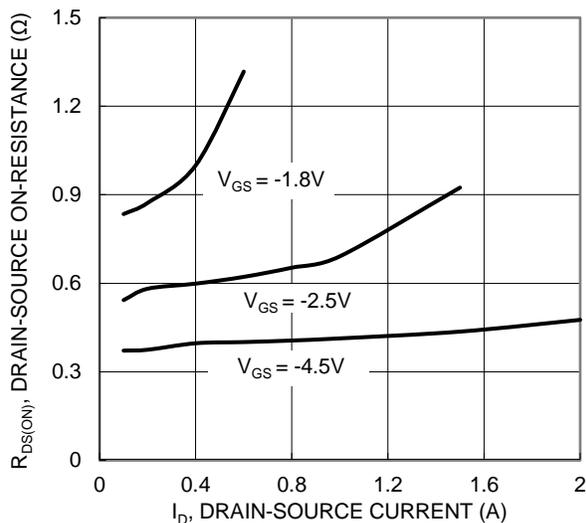


Figure 3. Typical On-Resistance vs. Drain Current and Gate Voltage

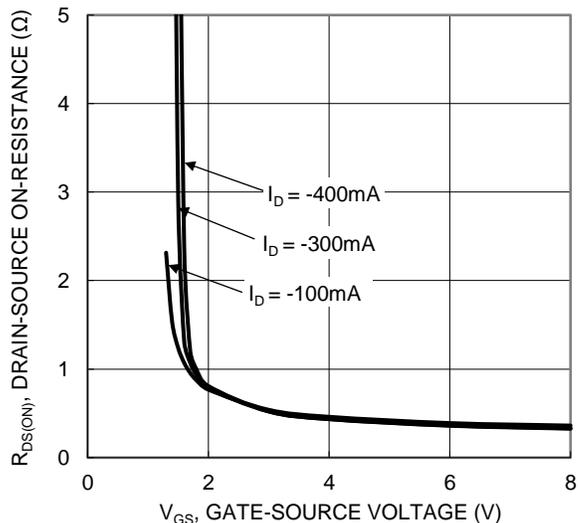


Figure 4. Typical Transfer Characteristic

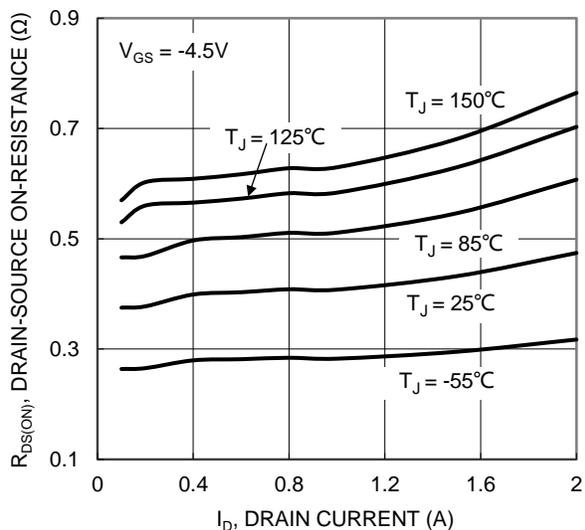


Figure 5. Typical On-Resistance vs. Drain Current and Junction Temperature

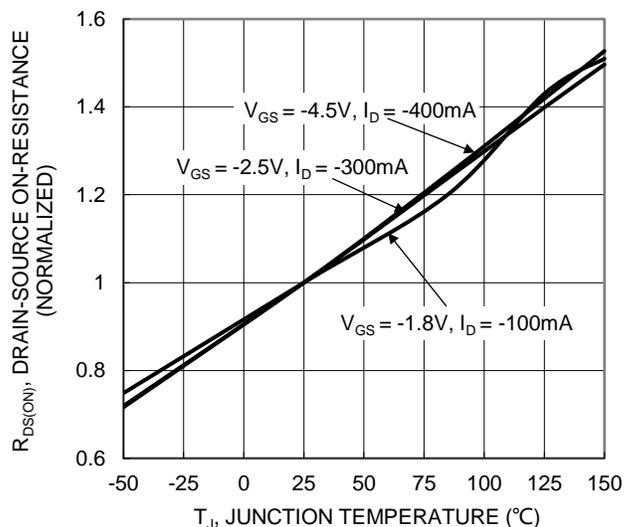


Figure 6. On-Resistance Variation with Junction Temperature

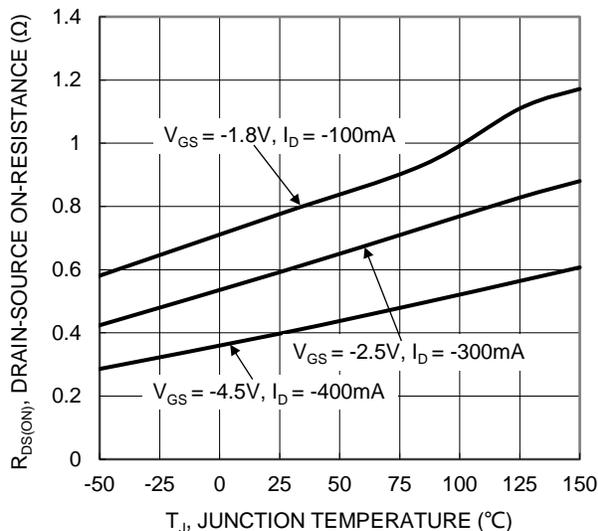


Figure 7. On-Resistance Variation with Junction Temperature

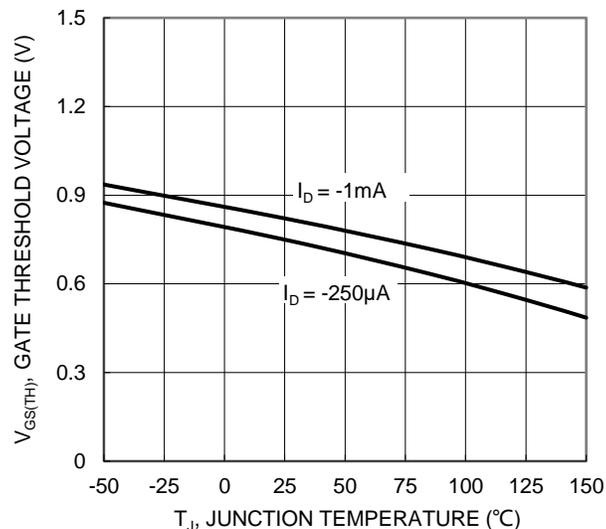


Figure 8. Gate Threshold Variation vs. Junction Temperature

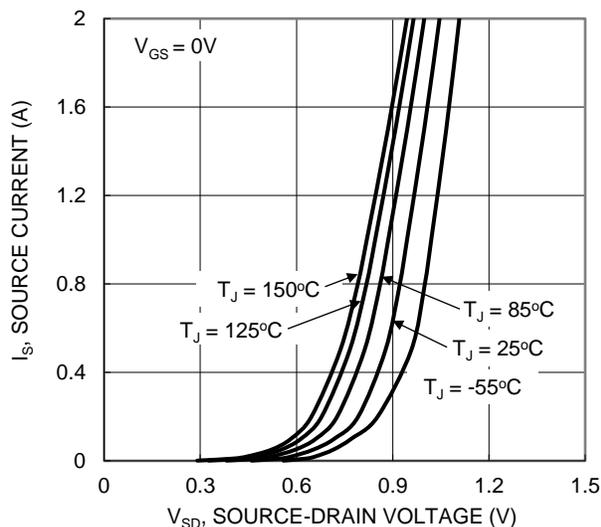


Figure 9. Diode Forward Voltage vs. Current

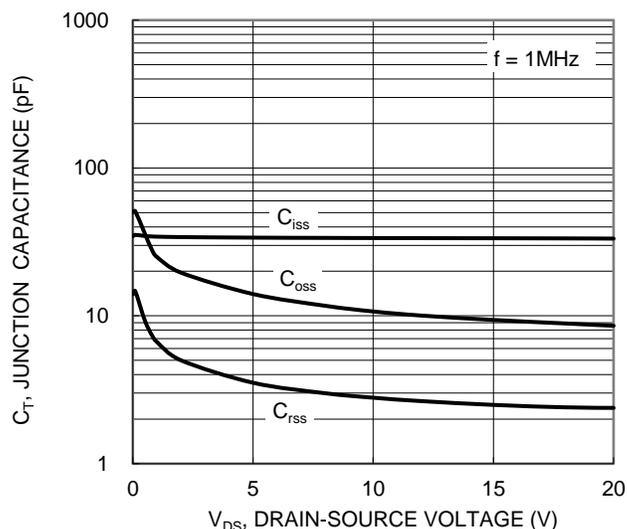


Figure 10. Typical Junction Capacitance

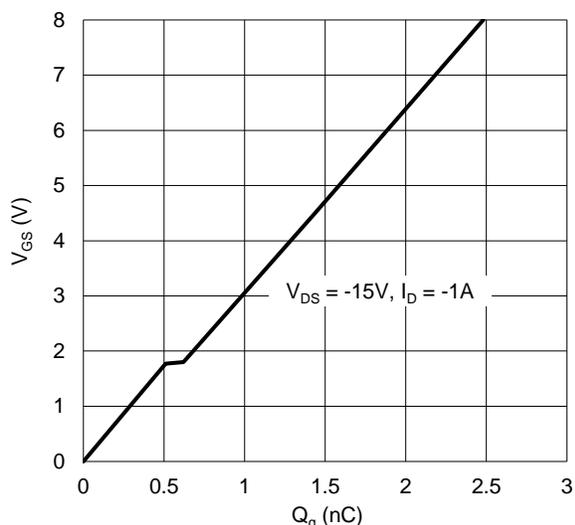


Figure 11. Gate Charge

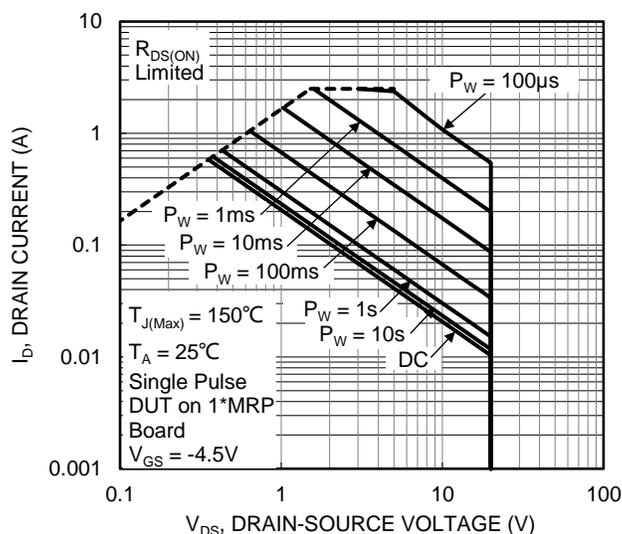


Figure 12. SOA, Safe Operation Area

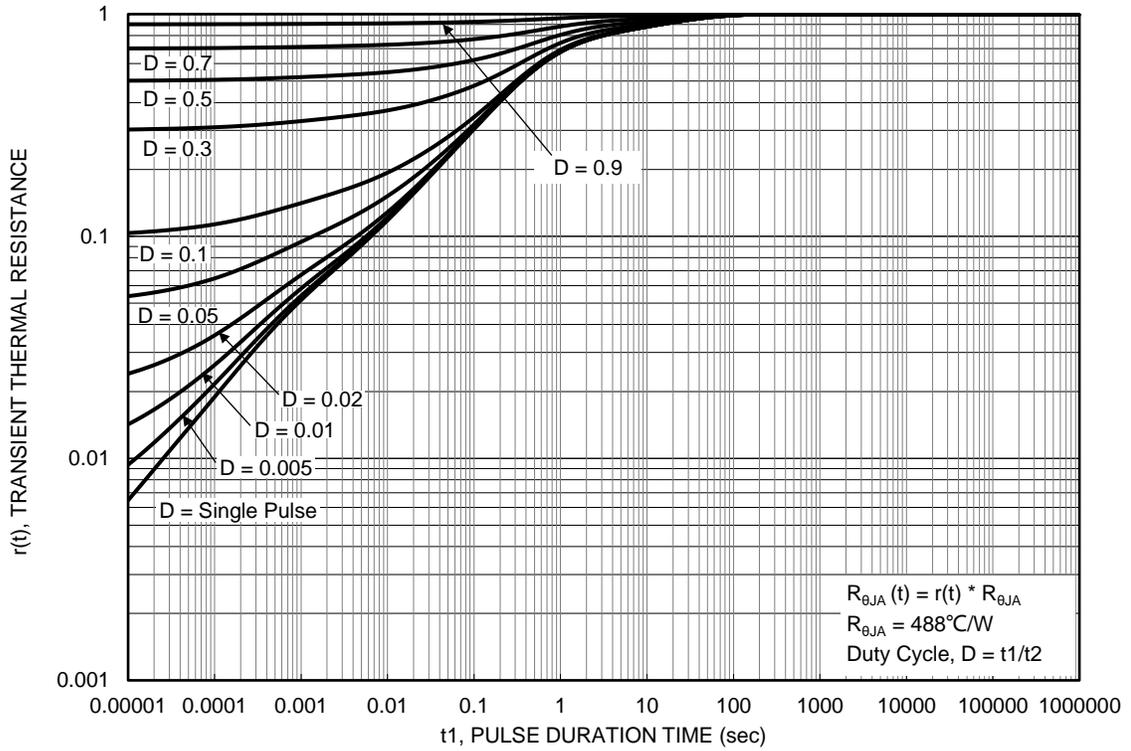


Figure 13. Transient Thermal Resistance

